

RECEIVED

JAN 0 9 2003

TC 1700

SHEET 1 OF I

GROUP 1762 2854

SUBSTITUTE FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

9325-58 (153520)

10/037,271

INFORMATION DISCLOSURE CITATION

APPLICANT: Scott W. Huffer

PILING DATE 11/7/2001

U.S. PATENT DOCUMENTS									
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	PILING DATE (IF APPROPRIATE		
RY	AA	5,116,548	05/26/92	Mallik et al.	264	1.3			
	AB	4,124,947	11/14/78	Kuhl et al.	40	453			
	AC	4,184,700	01/22/80	Greenaway	283	6			
	AD	5,401,303	03/28/95	Stoffel et al.	106	20 R			
	AE	1,509,664	09/23/24	Brown			`.		
	AF	2,793,585	05/28/57	Granitsas	101	28			
	AG	3,859,110	01/07/75	Foster et al.	117	27			
	AH	4,079,673	03/21/78	Bernstein	101	426			
	ΑI	4,908,063	03/13/90	Baker et al.	106	31			
	AJ	5,008,144	04/16/91	Baker et al.	428	211			
	AK	4,759,982	7/26/1988	Jennssen	428	343			
	AL	5,330,799	07/19/94	Sandor et al.	427	510			
	AM	5,538,674	07/23/96	Nisper et al.	264	1.31			
	AN	5,539,440	07/23/96	Higuchi et al.	347	112			
1	AO	5,554,432	09/10/96	Sandor et al.	428	157			
RY	AP	5,742,432	04/21/98	Bianco	359	566			

FOREIGN PATENT DOCUMENTS									
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLA SS	TRANSLATION YES	NO		
RY	0 569 640 A1	8/25/1992	EPO	B41M	1/30_				
	0 974 626 A1	1/26/2000	EPO	@ 9D -	11/00-				
	1 022 151 A1	7/27/1999	EPO	B41M	5/00				
	WO 00/37258	6/29/2000	PCT	Æ41M-	5/00				
RY	55-146785	11/80	Japan		-	X .			

examiner Len Jan	DATE CONSIDERED $8/22/03$
V	and the second s

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

PHIP\339597\1